

**Search Notes****Application/Control No.**

10/617,055

**Examiner**

Emeka Ebirim

**Applicant(s)/Patent under Reexamination**

LEE ET AL.

**Art Unit**

2166

**SEARCHED**

Class	Subclass	Date	Examiner
707	100	2/6/2006	EE
700	108	2/6/2006	EE
715	736	2/6/2006	EE

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/6/2006	EE
Consulted Pham Khanh (Primary)	2/6/2006	EE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner